

MILITARY SPECIFICATION
MICROCIRCUITS, DIGITAL, BIPOLAR, TTL,
MAGNITUDE COMPARATORS, MONOLITHIC SILICON

Inactive for new design after 8 July 1997

This amendment forms a part of MIL-M-38510/150C, dated 7 November 1985, and is approved for use by all Departments and Agencies of the Department of Defense.

PAGE 1

- * 1.2.1, circuit for device type 02: delete "4-Bit" and substitute "5-Bit".

PAGE 6

4.2a(1), delete and substitute as follows:

- "(1) Test condition D or E, using the circuit shown on figure 4, or equivalent. Test condition A and the applicable test circuit shall be allowed with the approval of the qualifying activity."

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TABLE III, device type 01, truth table tests, test numbers 55 through 70, pins 1, 2, 3, 4, 9, 10, 11, 12, 13, 14, and 15: Delete all "2.0 V" and substitute "2.4 V". Delete all "0.8 V" and substitute "0.4 V".

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4.4.3b(1), delete and substitute as follows:

- "(1) Test condition D and E, using the circuit shown on figure 4, or equivalent. Test condition A and the applicable test circuit shall be allowed with the approval of the qualifying activity."

The margins of this amendment are marked with an asterisk to indicate where changes (additions, modifications, corrections, deletions) from the previous amendment were made. This was done as a convenience only and the Government assumes no liability whatsoever for any inaccuracies in these notations. Bidders and contractors are cautioned to evaluate the requirements of this document based on the entire content irrespective of the marginal notations and relationship to the previous amendment.

CONCLUDING MATERIAL

Custodians:
Army - CR
Navy - EC
Air Force - 11

Preparing activity:
DLA - CC

Review activities:
Army - AR, MI, SM
Navy - AS, CG, MC, OS, SH, TD
Air Force - 19, 99

(Project 5962-1881)